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VN	AA	4,560,216		12/24/85	Egawa	wa							
	AB	4,754,555		7/5/88	Stillman	iillman							
,	AC	5,475,317		12/12/95	Smith	Smith							
<u> </u>	AD	5,495	5,667	3/5/96	Farnworth et	Farnworth et al.							
			on	HER REFERE	ENCES (includir	ng Author, Title, Date	, Pertinent Pages, I	Etc.)					
	ΑĒ		S/N: 09/032,184; Fil	ed 2/37/98; Ale	ram-ct-el.; Amcr	ndment filed 12/18/00,	CPA filed 7/28/90; .	Amendment filed	3/3/00; Amend	mont filed 8/23/9	<u>9;-</u>		
			Original Application filed 2/27/98, Pending Claims.										
VN	AF		Advertisement for Pro	obe Technology	; www.idinet.co	m; Interconnect Device	es, Inc., 1 page; 3/6.	/98					
VN	AG		Good Things Come In Small BGA/CSP Packages; www.johnstech.com/4/handbook/page9.html; 1 page; 3/5/98										
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VN	AH		Product Description f	or Double Ende	ed Probes, B1052	2 Series; <u>www.testprob</u>	e.com/products/b105	2.html; Rika Den	shi America, Ir	ic.; 1 page; 2/4/9	В.		
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VN	AI		Product Description for	or Test Centers.	, RM-500 Series	Probes, www.testprob	e.com/products/rm50	00.html; Rika Der	shi America, I	nc.; 1 page; 2/4/9	8.		
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VN	vī		Product Description for	or Cost Effectiv	e Interconnectio	ons for High I/O Produc	ts; www.testprobe.	com/products/io.l	ntm#b1303;_Ril	a Denshi America	a, Inc.;		
			1 page; 2/4/98.										
VN	<u>AK</u>		Product Description for	or Ball Grid Pro	obe B1303-C3; <u>v</u>	www.testprobe.com/pro	ducts/io.htm#b1303;	Rika Denshi Am	erica, Inc.; 1 pa	age; 2/4/98.			
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